

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In regard to the application of: Naor WAINER et al.

Serial No : US Divisional of 10/465,075

Group Art Unit: To be assigned

Filed : Herewith

Examiner: Unknown

For : PIXELATED PHOTON DETECTOR

INFORMATION DISCLOSURE STATEMENT

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

The present application is a divisional application under 35 U.S.C. §111(a) of U.S. Application No. 10/465,075 which is a divisional application under 35 U.S.C. §111(a) of U.S. Application No. 09/806,084 which is a national application under 35 U.S.C. §371 of PCT Application No. PCT/IL98/00462.

The Examiner is respectfully requested to review and consider art, in accordance with MPEP 2001.06 and to indicate in the first office action that he has considered this art. Additionally, the Examiner is respectfully requested to cite those prior art publications mentioned in this application which the examiner considers to be material or relevant to the present claims.

Further, in order to comply with discretionary regulations 37 C.F.R. §1.97 and §1.98, attached is Form PTO-1449 listing the cited art. This art contains information which the Examiner may consider to be important in deciding whether to allow the present application to issue as a patent.

Applicants wish to point out that the items 1-7 and 12-22 were cited in parent file 09/806,084, additionally, items 8-11 were cited by the Examiner in parent file 10/464,075. Copies of these items are not attached as they are available in the parent files.

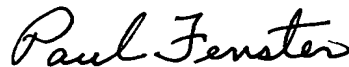
In accordance with MPEP Section 609 it is requested that each document cited (including any mentioned in Applicants' specification which is not repeated on the attached PTO-1449 form) be given thorough consideration and that it be cited of record in the

prosecution history of the present application by initialing on PTO-1449 form, so that it will appear on the face of the patent issuing on the present application, even if the Examiner does not consider it sufficiently pertinent to use in a rejection, or otherwise does not believe that the guidelines for citation have been fully complied with.

The present Information Disclosure Statement is being submitted in compliance with 37 C.F.R. §1.56 as an Examiner might consider any cited document important in deciding whether to allow the application to issue as a patent, but the citation of each document is not to be construed as an admission that such document is necessarily relevant or prior art. No representation is intended that the cited documents represent the results of a complete search, and it is anticipated that the Examiner in the normal course of examination, will make an independent search and will determine the best prior art consistent with 37 C.F.R. §1.104(a), and in the course of such search will review for relevance every document cited on the attached form even if not initialed.

Early and favorable consideration is earnestly solicited.

Respectfully submitted,
Naor WAINER et al.



Paul Fenster,
Registration No. 33,877

March 23, 2004

William H. Dippert, Esq.
Reed Smith LLP
599 Lexington Avenue, 29th Floor
New York, NY 10022-7650

Tel.: (212) 521-5400

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				ATTY DOCKET NO. 037/03962		SERIAL NO. US Div'l of 10/465,075	
				Naor WAINER et al.			
				FILING Herewith		GROUP To be assigned	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	1	DOCUMENT NUMBER 4,210,805	DATE 1 Jul '80	NAME KOBAYASHI, T. et al.	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	2	4,755,676	5 Jul '88	GAALEMA, S. et al.			
	3	5,677,539	14 Oct '97	APOTOVSKY, B. et al.			
	4	5,777,338	7 Jul '98	HE, Z.			
	5	5,821,539	13 Oct '98	MATZ, R. et al.			
	6	6,034,373	7 Mar '00	SHAHAR, A. et al.			
	7	6,169,287	2 Jan '01	WARBURTON, W. K.			
	8	6,583,420	June 2003	NELSON, et al.			
	9	6,333,504	Dece 2001	LINGREN, et al.			
	10	2002/0079456	June 2002	LINGREN, et al.			
	11	5,500,534	March 1996	ROBINSON, et al.			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	12	CH 471 392	15 Apr '69	SWITZERLAND			
	13	DE 196 16 545	30 Oct '97	GERMANY			
	14	EP 0 291 351	17 Nov '88	EUROPE			
	15	EP 0 527 373	17 Feb '93	EUROPE			
	16	FR 2 705 791	2 Dec '94	FRANCE			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
	17	HE, Z. et al.; "Coplanar Grid Patterns and Their Effect on Energy Resolution of CdZnTe Detectors;" IEEE Nuclear Science Symposium and Medical Imaging Conference; Albuquerque, Mexico; 9-15 November 1997					
	18	NAOAKI, I.; JP 02-163691 A; 22 June 1990 & Patent Abstracts of Japan; Vol. 014; No. 422 (P-1104); 12 September 1990					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

